

<b>Notice of References Cited</b>	Application/Control No. 09/706,274	Applicant(s)/Patent Under Reexamination ARNEY ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gabriel, C. et al, Chemical Abstracts 1995, 122, abstract 175490z.
	V	Fabianowski, W. et al, Advanced Materials for Optics and Electronics 1995, 5, 199-213.
	W	Ziaie, B. et al, Journal of Microelectromechanical Systems 1996, 5, 166-179.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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